


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530445	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Hanh Phan	<b>Art Unit</b>  2613

SEARCHED			
Class	Subclass	Date	Examiner
398	79, 81, 82, 91, 93, 94, 95, 100, 66, 67, 68, 70, 71, 72, 140, 141, 153, 156, 158, 159, 163, 192, 195, 196, 197, 13, 14, 17, 20, 21, 25, 26, 27, 31, 33, 38, 177	07/29/2008	HP
385	24, 37, 15, 14, 27	07/29/2008	HP
372	32, 34, 35, 36, 38.02	07/29/2008	HP
UPDATE SEARCH		07/29/2008	HP

SEARCH NOTES		
Search Notes	Date	Examiner
EAST SEARCH SEE ATTACHED PRINTOUT IN THE FILE	07/29/2008	HP
IEEE SEARCH	07/29/2008	HP
JPO SEARCH	07/29/2008	HP
PG PUB TEX SEARCH SEE INTERFERENCE SEARCH PRINTOUT	07/29/2008	HP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
398	79, 81, 82, 91, 93, 94, 95, 100, 66, 67, 68, 70, 71, 72, 140, 141, 153, 156, 158, 159, 163, 192, 195, 196, 197, 13, 14, 17, 20, 21, 25, 26, 27, 31, 33, 38, 177	07/29/2008	HP
385	24, 37, 37, 14, 15	07/29/2008	HP
372	32, 34, 36, 35, 38.02	07/29/2008	HP